## AMENDMENTS TO THE CLAIMS

This listing of claims replaces all prior versions, and listings, of claims in the application.

Claims 1-6 (Cancelled).

7. (Currently Amended) An underlayer film for copper, disposed on a substrate, wherein

the film is formed such that a  $(R_1R_2)P$ - $(R)_n$ -Si group-bonds of the underlayer film is bonded to the substrate via an Si-O bond,

R<sub>1</sub> and R<sub>2</sub> each represent an alkyl group,

R represents a divalent linear organic group selected from the group consisting of an alkylene group, an aromatic ring, and an alkylene group including an aromatic ring, and n is an integer from 1 to 6.

8. (Currently Amended) An underlayer film for copper according to claim 7, wherein the film is formed by a method including bringing an underlayer film-forming material for copper, including a compound represented by the following formula [I], into contact with a surface of a substrate,

$$(R_1R_2)P-(R)_n-Si(X_1X_2X_3)$$
 [I]

wherein

at least one of  $X_1$ ,  $X_2$ , and  $X_3$  represents a hydrolysable group

 $R_1$  and  $R_2$  each represent an alkyl group;

R represents a divalent linear organic group selected from the group consisting of an alkylene group, an aromatic ring, and an alkylene group including an aromatic ring; and n represents an integer from 1 to 6.

9. (Currently Amended) A semiconductor device comprising:

a substrate;

an underlayer film for copper arranged on the substrate; and

a <u>copper</u> wiring film<del>, mainly copper, and</del> arranged on the underlayer film for copper, wherein

the underlayer film for copper is formed so that an  $(R_1R_2)P$ - $(R)_n$ -Si group bonds of the underlayer film is bonded to a substrate via an Si-O bond,

 $R_1$  and  $R_2$  each represent an alkyl group;

R represents a divalent linear organic group selected from the group consisting of an alkylene group, an aromatic ring, and an alkylene group including an aromatic ring; and n is an integer from 1 to 6.